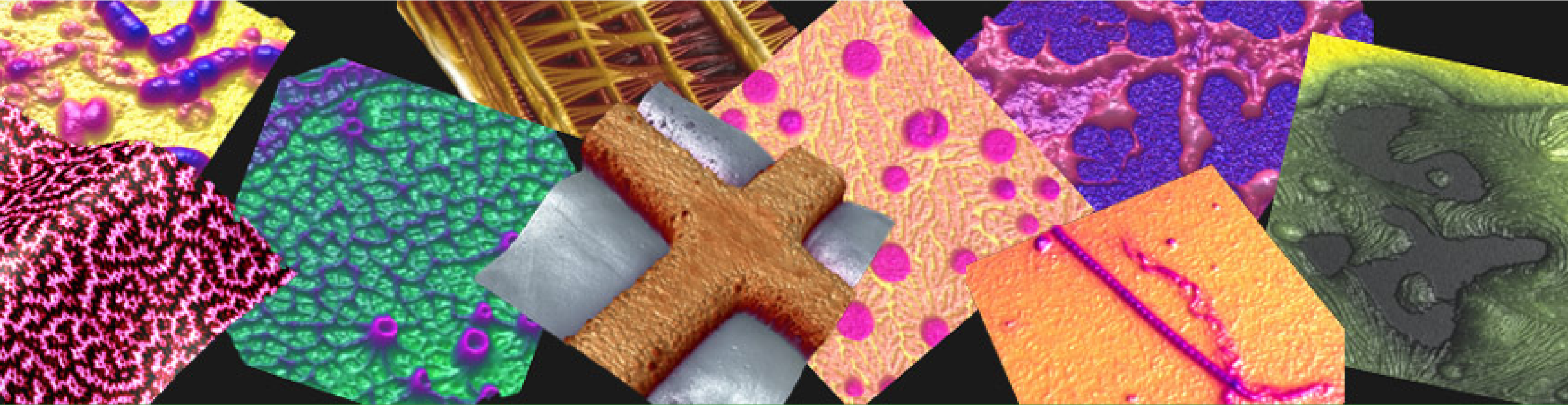

University of Hawaii, Bruker and Renishaw present Advanced AFM and AFM-Raman Workshop

AFM has been used for many years for ultra high-resolution microscopy and has earned a reputation as a powerful but complex tool. Recent advances by Bruker are making AFM easier to use, providing more unambiguous and quantitative information, and extending the ability of AFM to provide Nanoscale Chemical-ID information in addition to quantitative adhesion, modulus and mechanical property while working with the most challenging samples. These advances include **ScanAsyst** mode, **PeakForce QNM** and **IRIS – integrated AFM Raman Imaging System.**

Thursday July 12 - 10:30am - 12 pm:

Technical Talks:

1. **AFM Imaging – Beyond Topography -Mayur Savla, Bruker Nano Inc.**
2. **Raman-AFM: towards nanoscale chemical and structural imaging -Dr. Andrew King, Renishaw Inc., Spectroscopy Product Division**

Thursday July 12 - 9:00am - 4pm:

Multimode-8 demo & imaging customer samples

Location: Holmes Hall, Rm # 389

Registration and more information:

Dr. Atul Tiwari
Associate Researcher
University of Hawaii
tiwari@eng.hawaii.edu

Mayur Savla
Applications Engineer, Bruker Corp.
Mayur.Savla@bruker-nano.com
614.209.5410